



#### **Example 2 Control Control**

## **Principle of Anomaly Detection**

- Active field of Data Science Involve state of the art Machine Learning algorithms
  - Many applications in **various scientific field** as well as in everyday life
- Example of anomalies

		time	variable	
	1	0	19.3	
80000		1	20.3	

# New silicon central detector for ATLAS (ITk)

– Upgrade toward HL-LHC More <u>luminosity</u> => more <u>challenges</u>

### New silicon central detector : ITk High precision particle tracking and high <u>radiation</u> <u>hardness</u>

- Pixel module production in Japan
   <u>2800 pixel modules</u> produced in Japan for ITk
  - Each component must be carefully assembled and



# checked <u>Mass production</u> starts in 2024 Flexible PCB (Yamashita Mat.) <u>Sensor Tile (HPK)</u> <u>FE Chip (TSMC)</u> Schematic of a ITk pixel module

# **Anomaly Detection and Quality Control**

- Important part of the production chain
   Make sure that every components of the detector is in perfect working condition
  - Must accommodate a rate of **8 modules per day** during mass production
- Visual Inspection at every step
   Search for visible defect on each component at

# Algorithms

– Unsupervised learning

**Objective:** identify <u>rare and new</u> types of defects

Unsupervised deep Neural Network (Auto-Encoder) => Identify <u>anomalous area</u> within a image

Filtering algorithm based on DBSCAN clustering => Isolate and highlight <u>major defect candidates</u> **Unsupervised workflow is fully functional** 

each step of production

Manual Visual inspection by human operators



Photo of the imaging setup

=> Time consuming (8~10 min)
=> Unreliable

<u>Computer Visual Inspection</u> => Fast (<1 min) => Reliable

<u>Anomaly Detection</u> using <u>Computer Vision algorithms</u> Supervised learning
 Objective: Categorize known and recurrent defect
 Deep Computer Vision model inspired by Detectron2
 => Identify common defect categories
 Integration with the unsupervised tool

Data preparation and training ongoing

# Results

Unsupervised identification example
 Training using ~50 <u>high resolution images of Flex PCB</u>
 => Use data augmentation techniques

Test on image where a <u>new defect</u> have been found => single occurrence anomaly



## Next steps

Near future schedule

First demonstration QC software including ML (only unsupervised) Full test of supervised algorithm

Final version of QC software including ML



#### The anomaly have been properly identified

Time required to process the <u>full image</u> : <10s => Fast inference using CPU only *(both supervised and unsupervised)* Deployment at production site in Japan

Global deployment of the ML tool for ITk production (To be confirmed)

Long term plan

Preparation of a <u>generic Anomaly Detection tool</u> for **Visual Inspection** of detector components

Aiming to reach <u>beyond ATLAS and other LHC</u> <u>experiments</u>





**Dec 22** 

Jan (end)

FY2024

2024